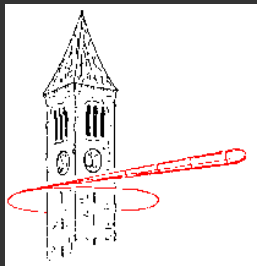




Cornell University

Thermal emittance and response time from NEA photocathodes

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**Cornell High Energy
Synchrotron Source**





- Theoretical maximum beam brightness
- Introduction to NEA cathodes
- Inelastic scattering mechanisms
- Diffusion model
- Thermal emittance & response time
- Temporal laser pulse shaping

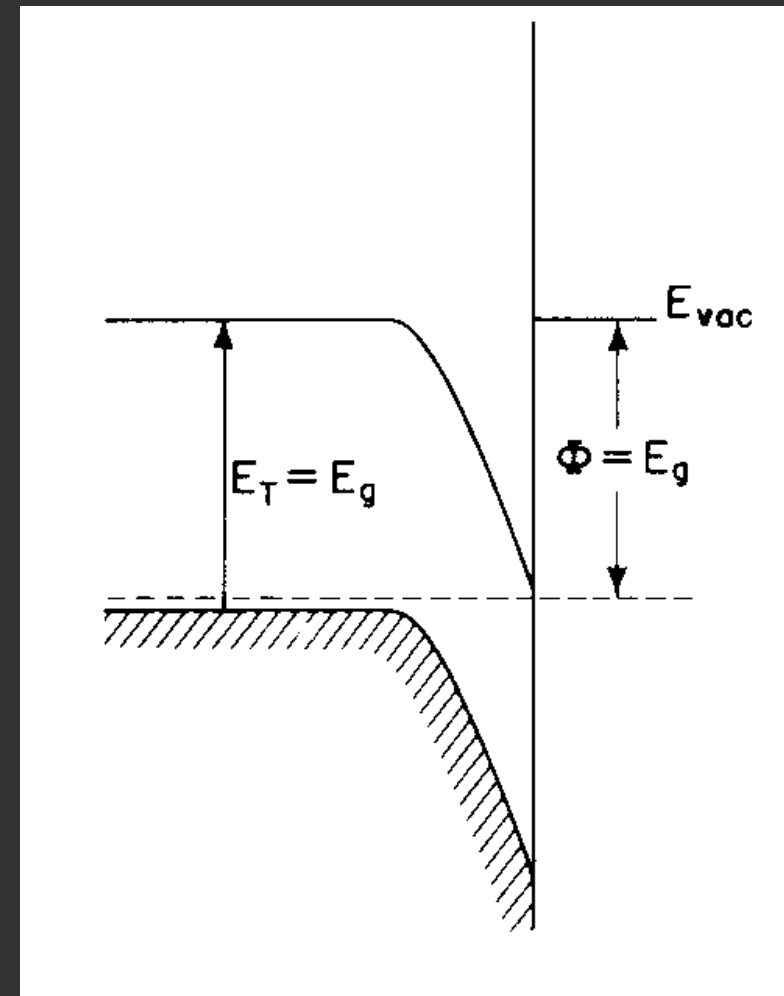


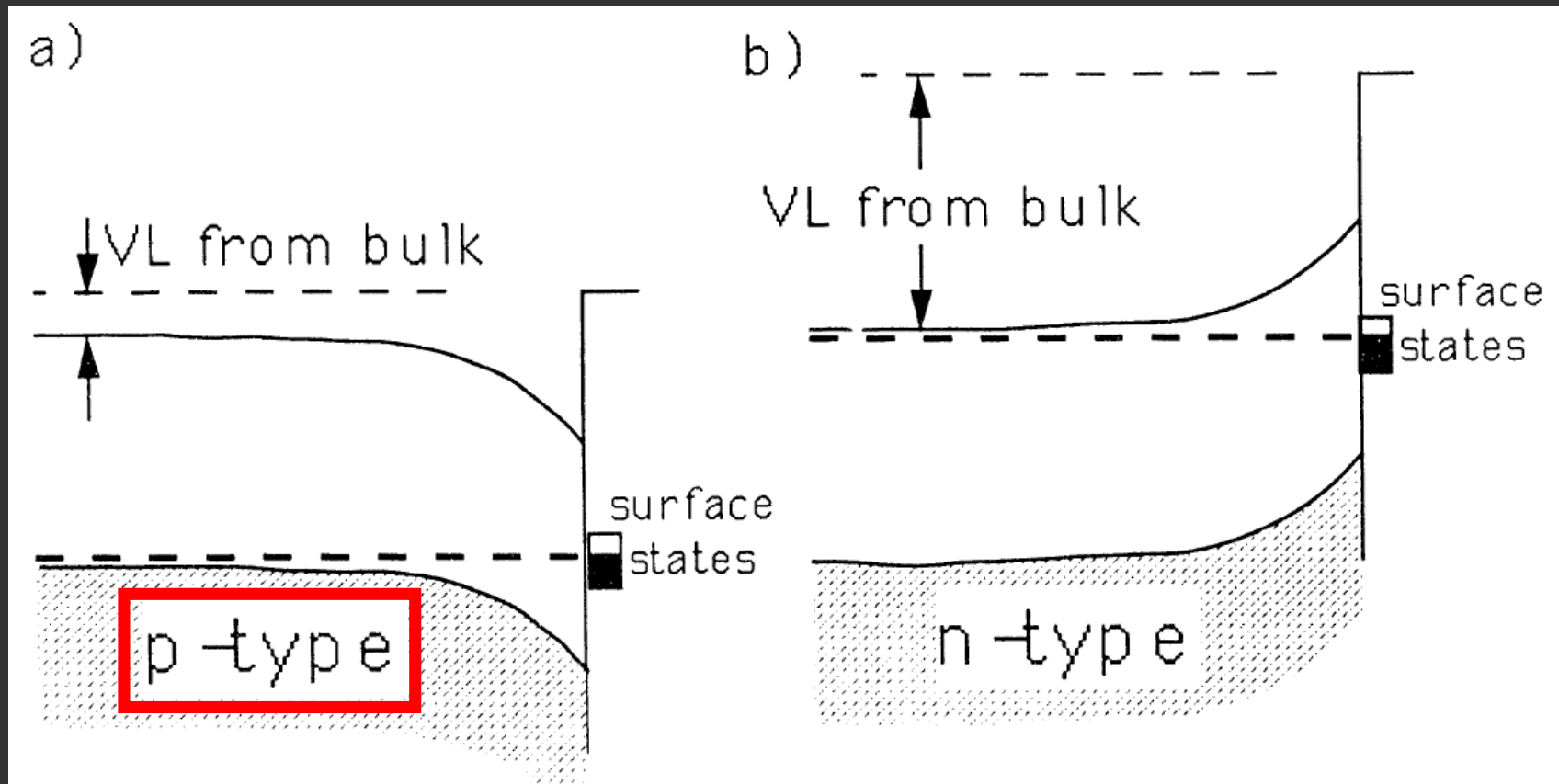
- Assuming a **pan-cake** bunch at the cathode [$\sigma_t \ll (\sigma_x m / e E_{\text{cath}})^{1/2}$] **max charge density** that can be extracted **$dq/dA = \epsilon_0 E_{\text{cath}}$**
- For Gaussian distribution of transverse momenta characterized by thermal energy kT , **$\langle p_x^2 \rangle = mkT$**
- Normalized average beam brightness ($\Delta x, \Delta p_x \dots$ ellipse half-axes) **$B_{n,\text{avg}} \equiv I_{\text{avg}}(mc)^2 / (\pi \Delta x \Delta p_x \pi \Delta y \Delta p_y)$**
- Max brightness per bunch:

$$\frac{B_{n,\text{avg}}}{f} = \frac{\epsilon_0 mc^2}{8} \frac{E_{\text{cath}}}{kT}$$



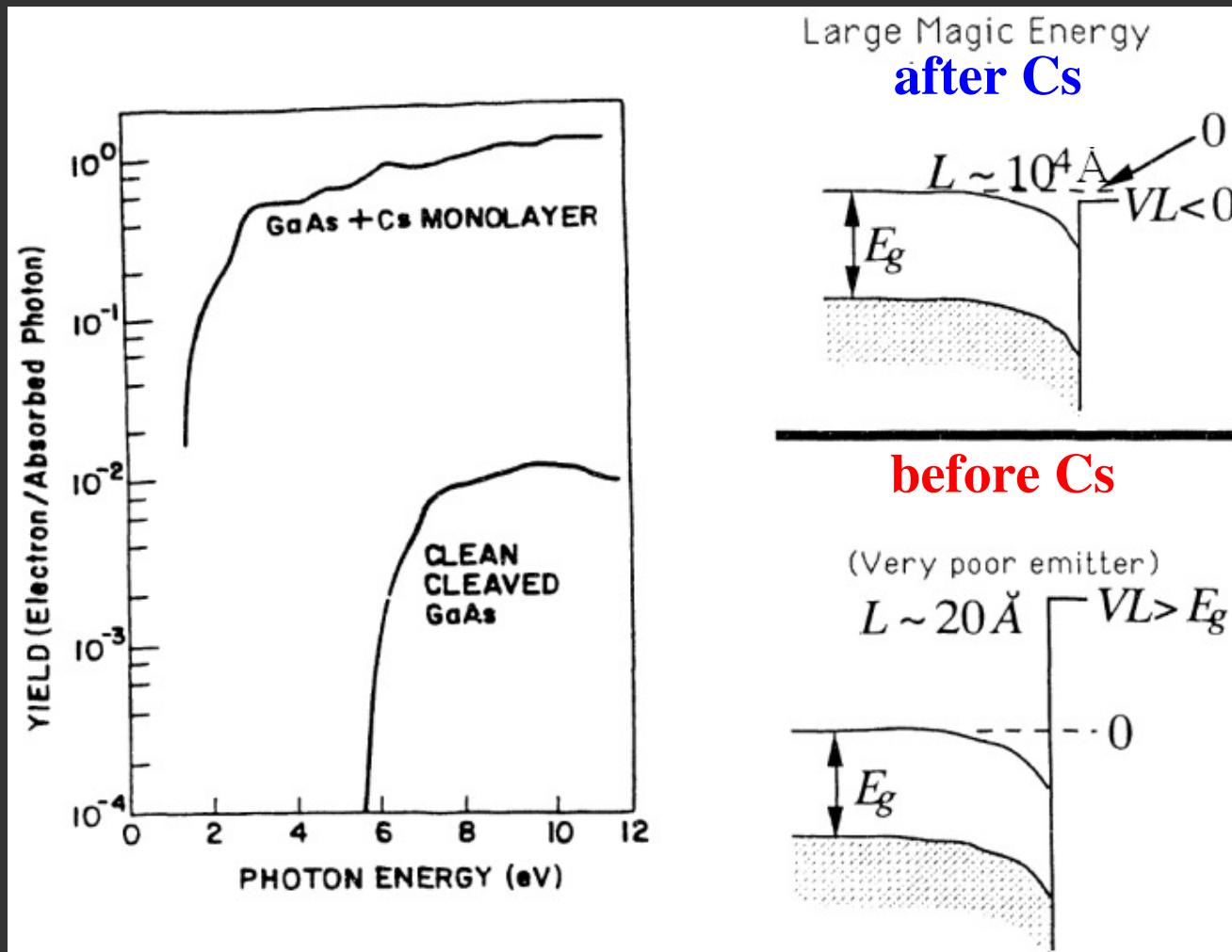
- Defined as vacuum level E_{vac} relative to the bottom of conduction band
- Negative affinity means the vacuum level lies below the conduction band minimum \Rightarrow very high QE
- *Surface condition* induces a *space charge*, which may bend the bands either up or down





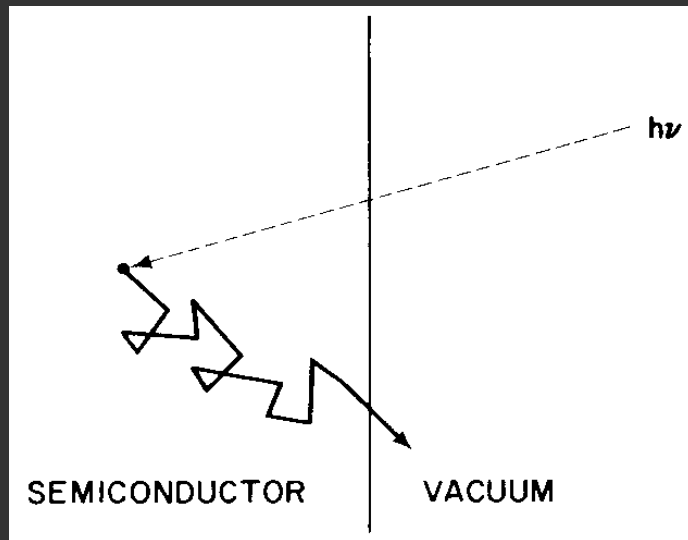


If thickness of a **low work function material** \ll **mean free path**
 \Rightarrow e^- can traverse the surface material without much loss
 \Rightarrow better quantum efficiency / reduced threshold





Spicer's 3-step model



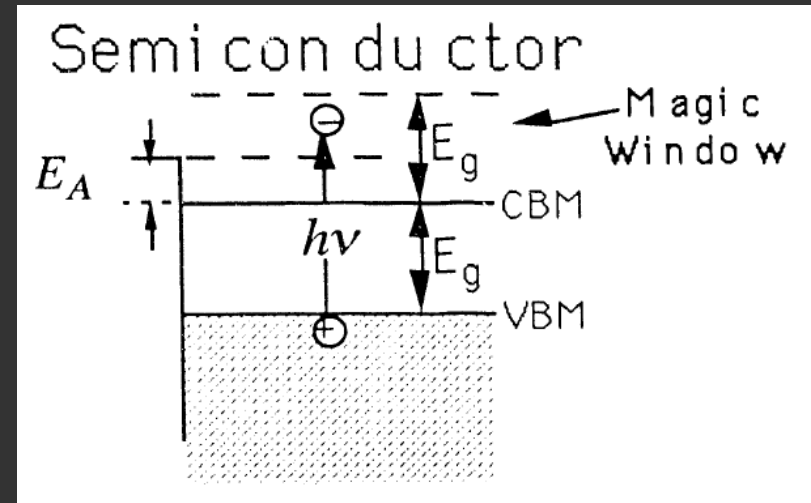
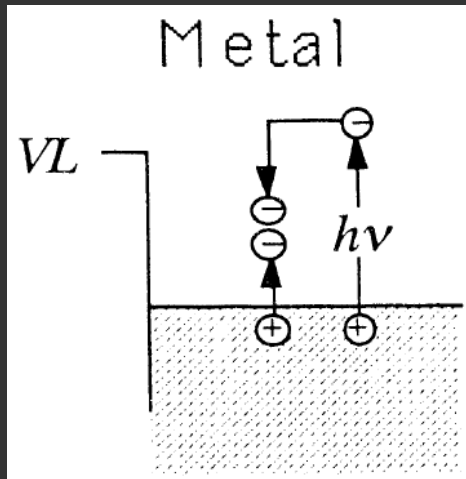
1. **photon excites electron** to a higher-energy state;
2. **electron-phonon scattering** (~ 0.01 – 0.05 eV lost per collision);
3. **escape with kinetic energy in excess** to E_{vac}

In GaAs the **escape depth is long** enough that a **large fraction of electrons are thermalized** to the bottom of the conduction band before they escape.

Response time $\sim (10^{-4} \text{ cm}) / (10^7 \text{ cm/s}) = \sim 10 \text{ ps}$
strong wavelength dependence!



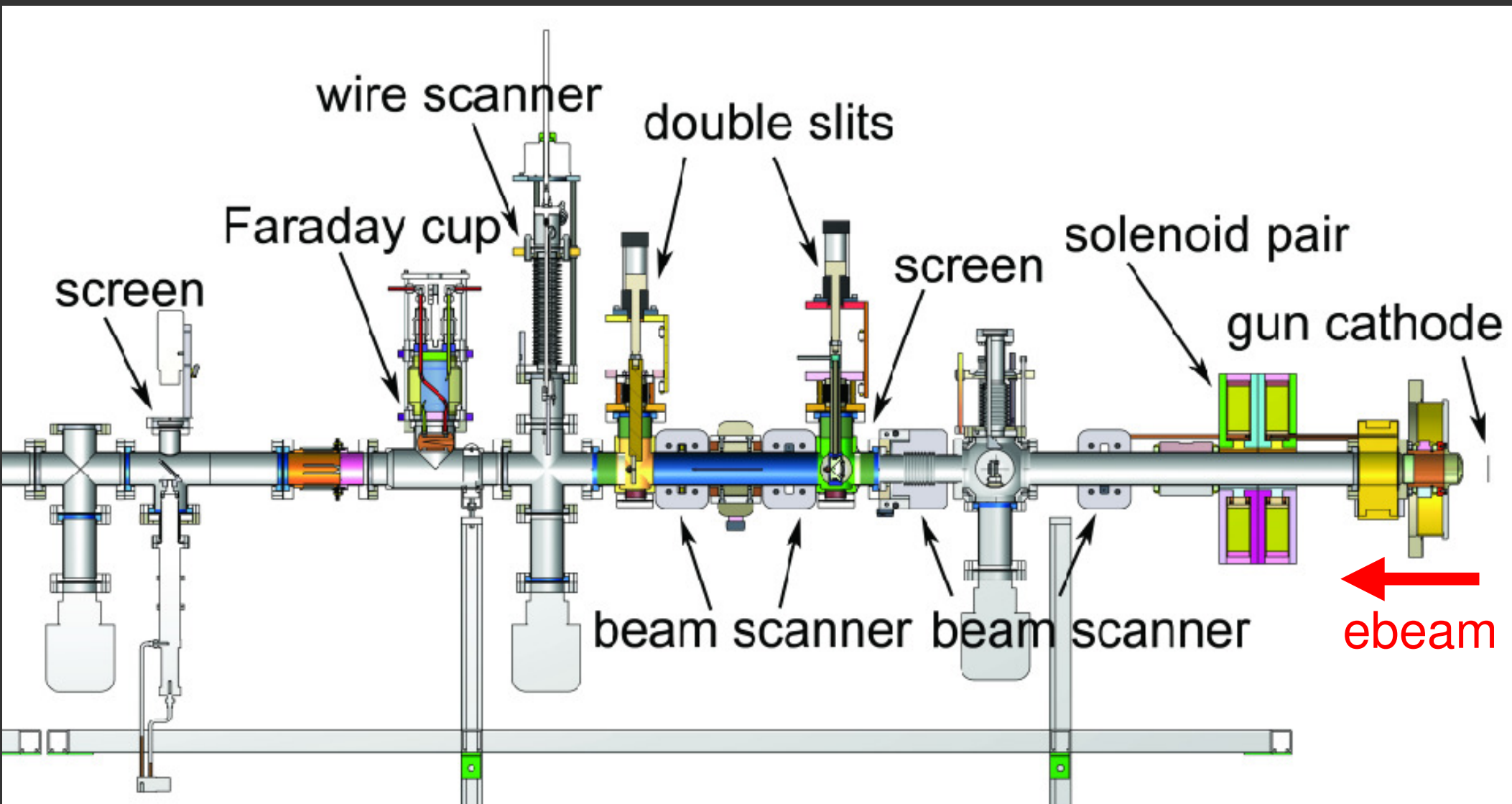
Inelastic scattering



- (1) **Electron-electron** scattering: occurs in metals, large energy loss per collision
- (2) **Electron-phonon** scattering: slowly depletes excessive energy of excited electron
- (3) **“Magic window”**: in semiconductors, one needs excess $KE > E_{\text{gap}}$ for e^-/e^- scattering. Thus, electrons excited with $E_{\text{vac}} < KE < E_{\text{VBM}} + 2E_{\text{gap}}$ have excellent chances of escape (high QE)



- **Thermal emittance** was measured as a function of laser wavelength for **GaAs** and **GaAsP** ($P = 45\%$)
$$\varepsilon_{n,th} = \sigma_{\perp} \sqrt{\frac{kT}{mc^2}}$$
- Emittance was **measured by solenoid scan** using a wirescanner for **different laser spot sizes and profiles**
- Essential to take data for various laser spot sizes, **cross-check between various methods** (e.g. solenoid scan and double-slits, viewscreen & wirescanner)
- See J. App. Phys. **103** (2008) 054901 for details



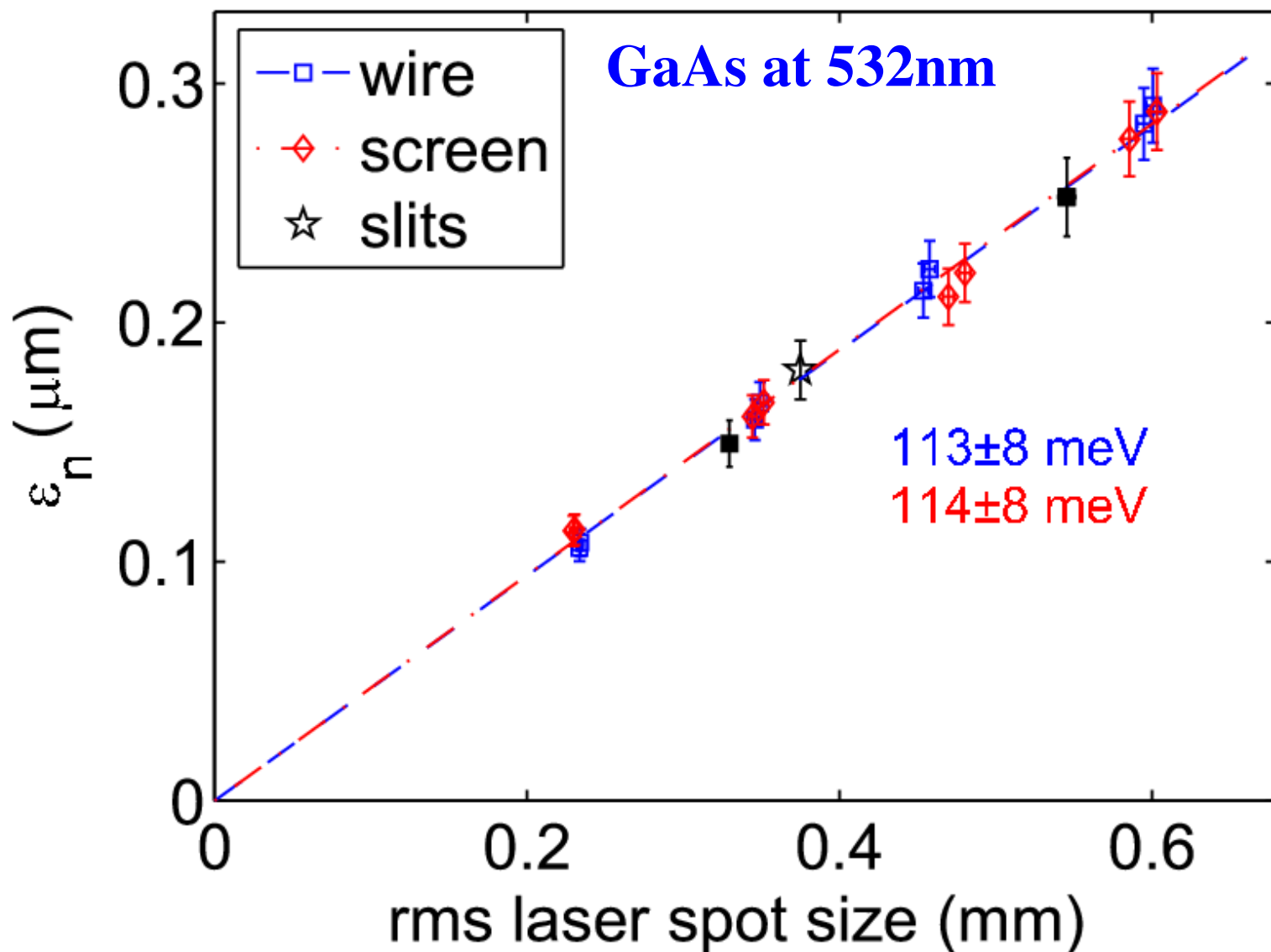
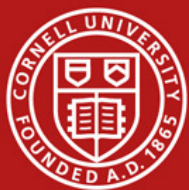
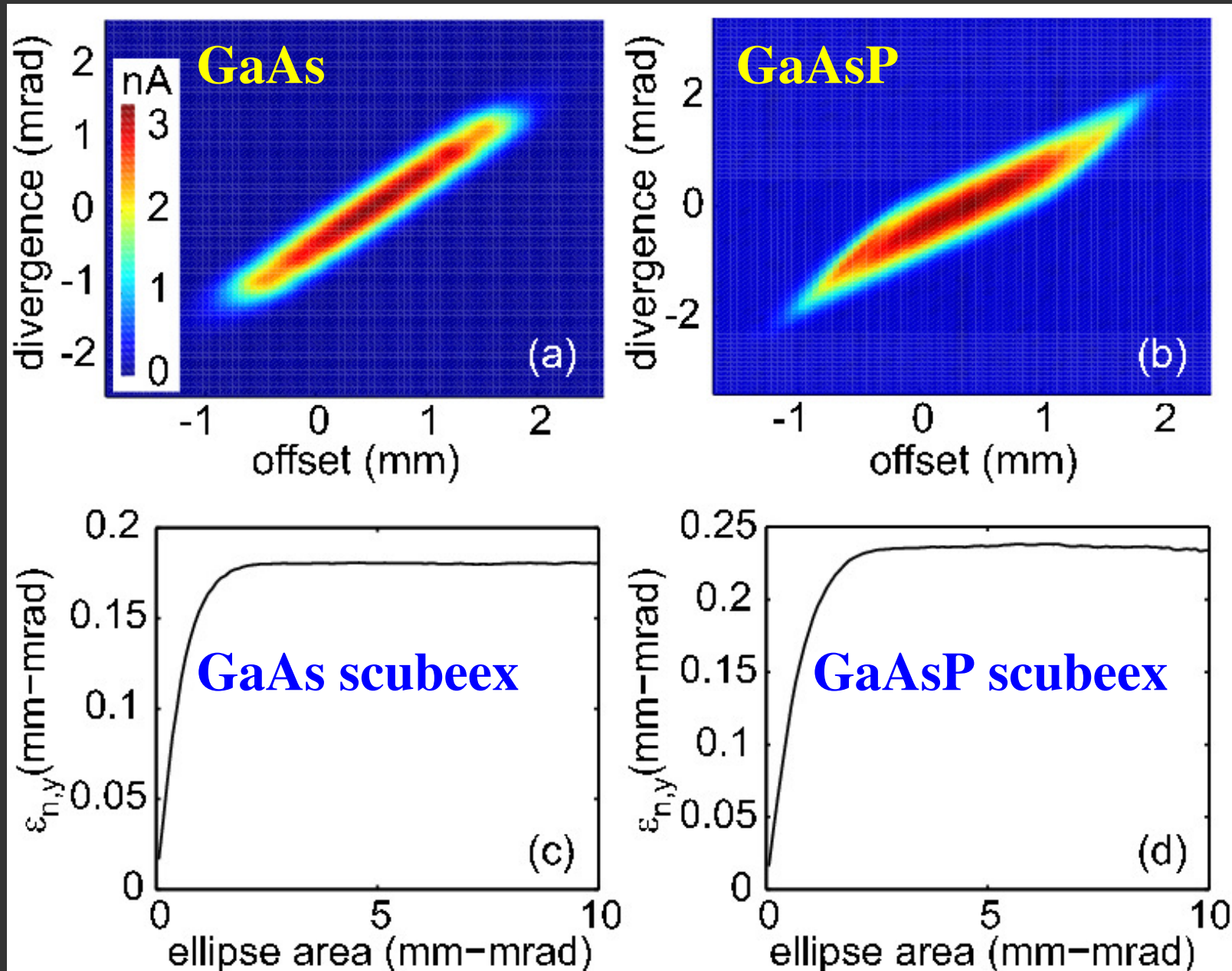
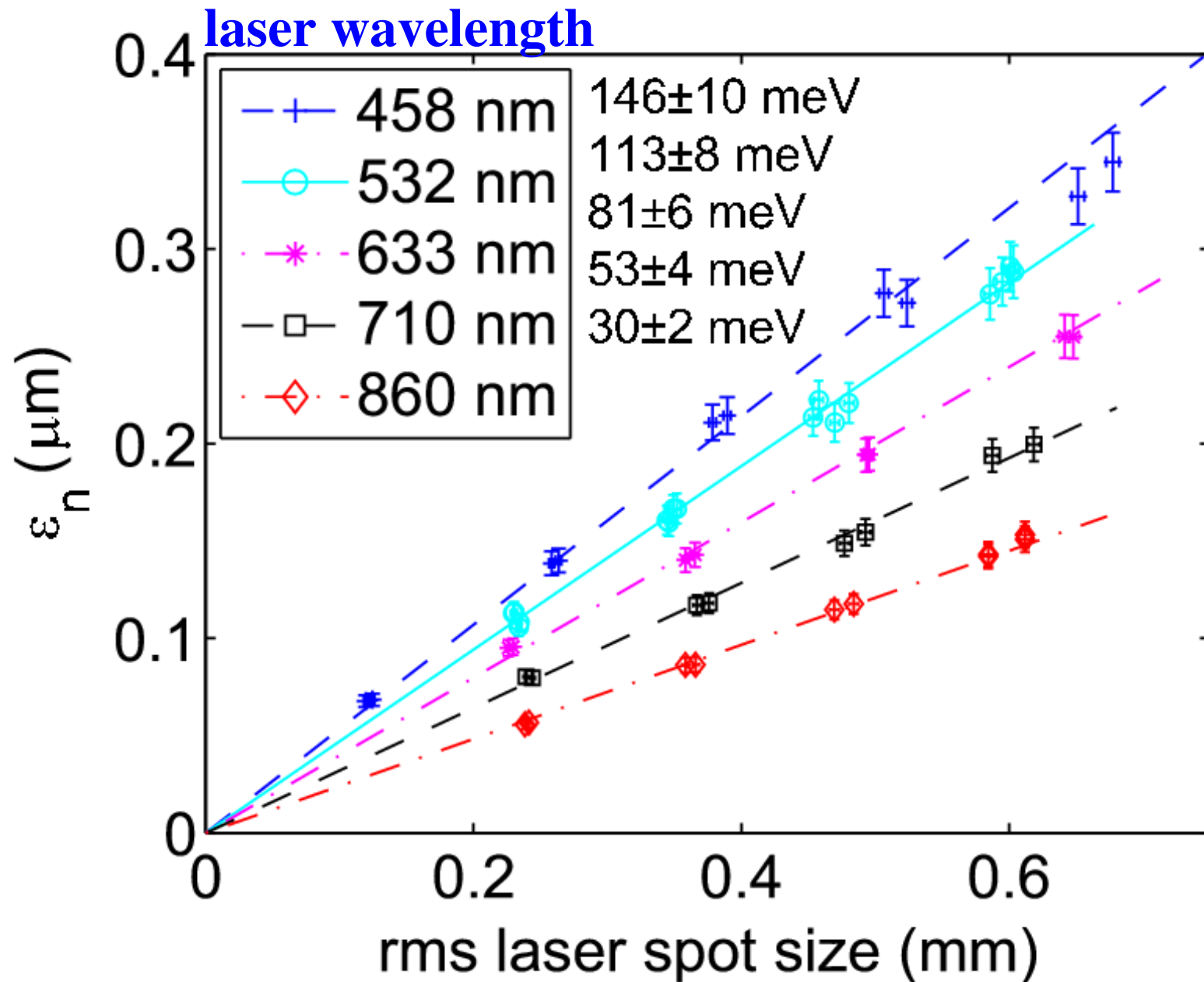


FIG. 5: Comparison between different emittance measurement techniques for GaAs at 532 nm. Filled squares correspond to a Gaussian laser profile.





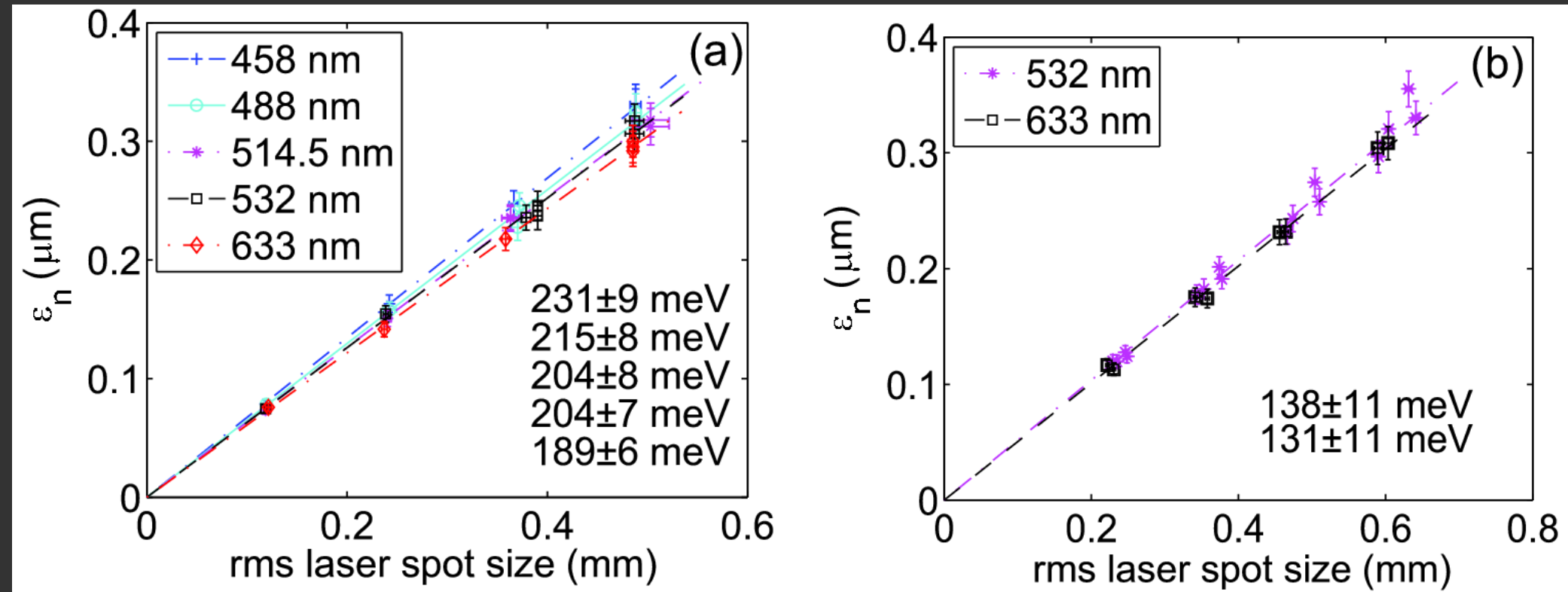
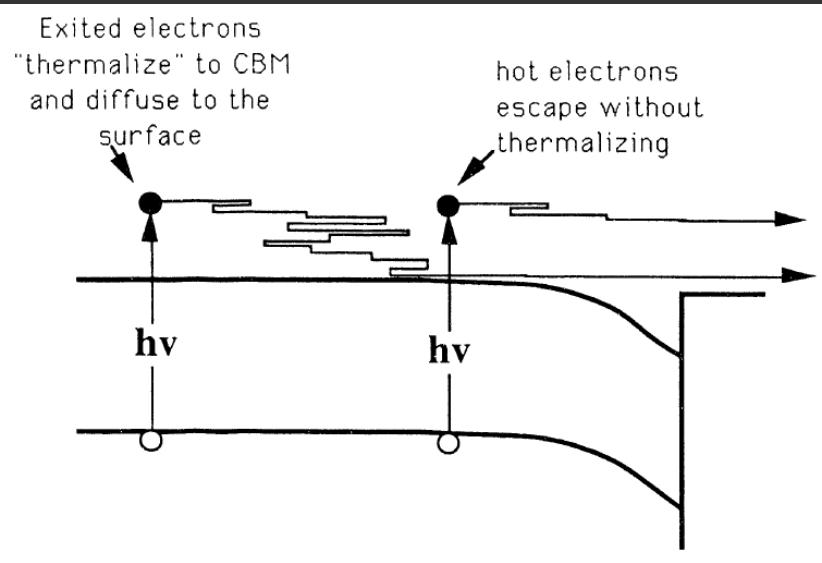
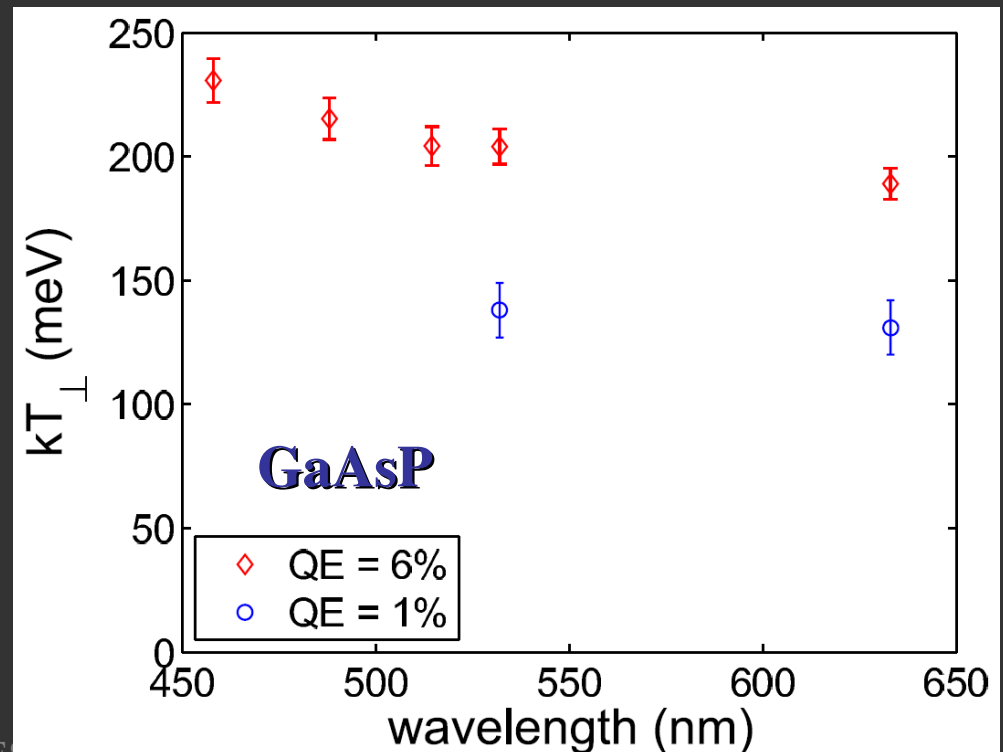
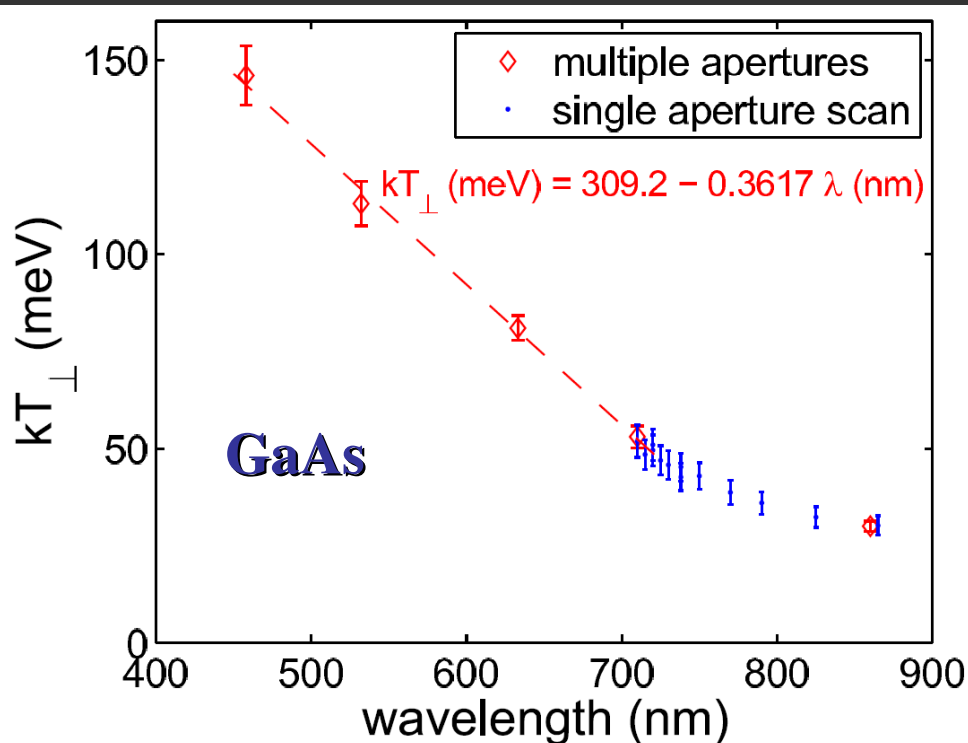


FIG. 7: Thermal emittance of GaAsP as a function of rms laser spot size. (a) QE = 6%. (b) QE = 1%. **can see QE effect on thermal emittance for GaAsP!**



relates spot size to emittance

$$\varepsilon_{n,th} = \sigma_{\perp} \sqrt{\frac{kT}{mc^2}}$$

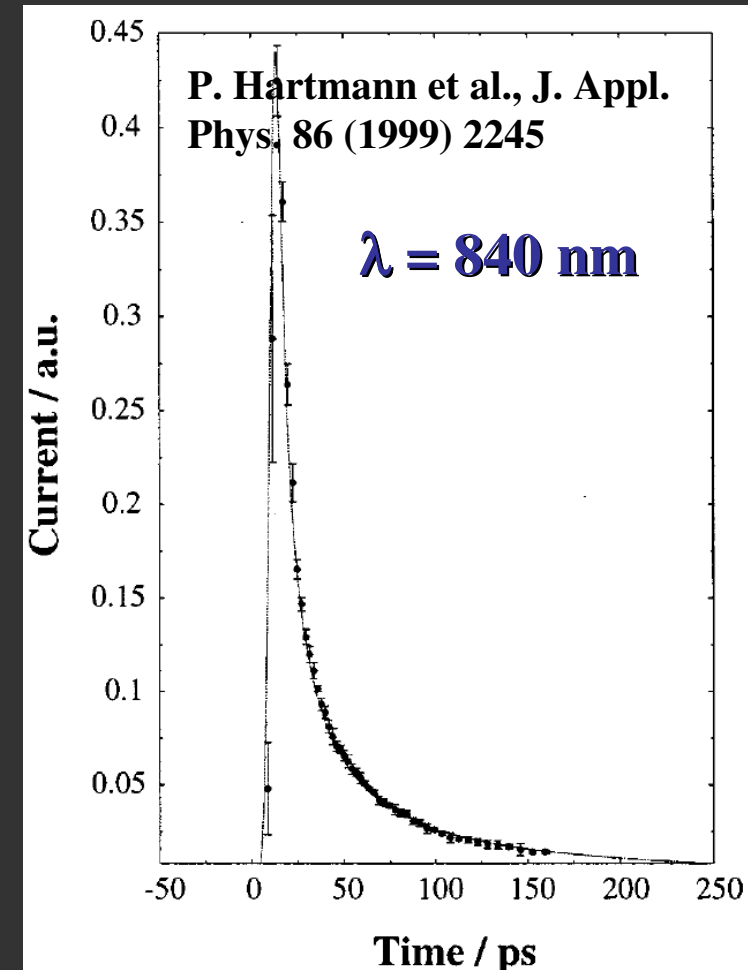
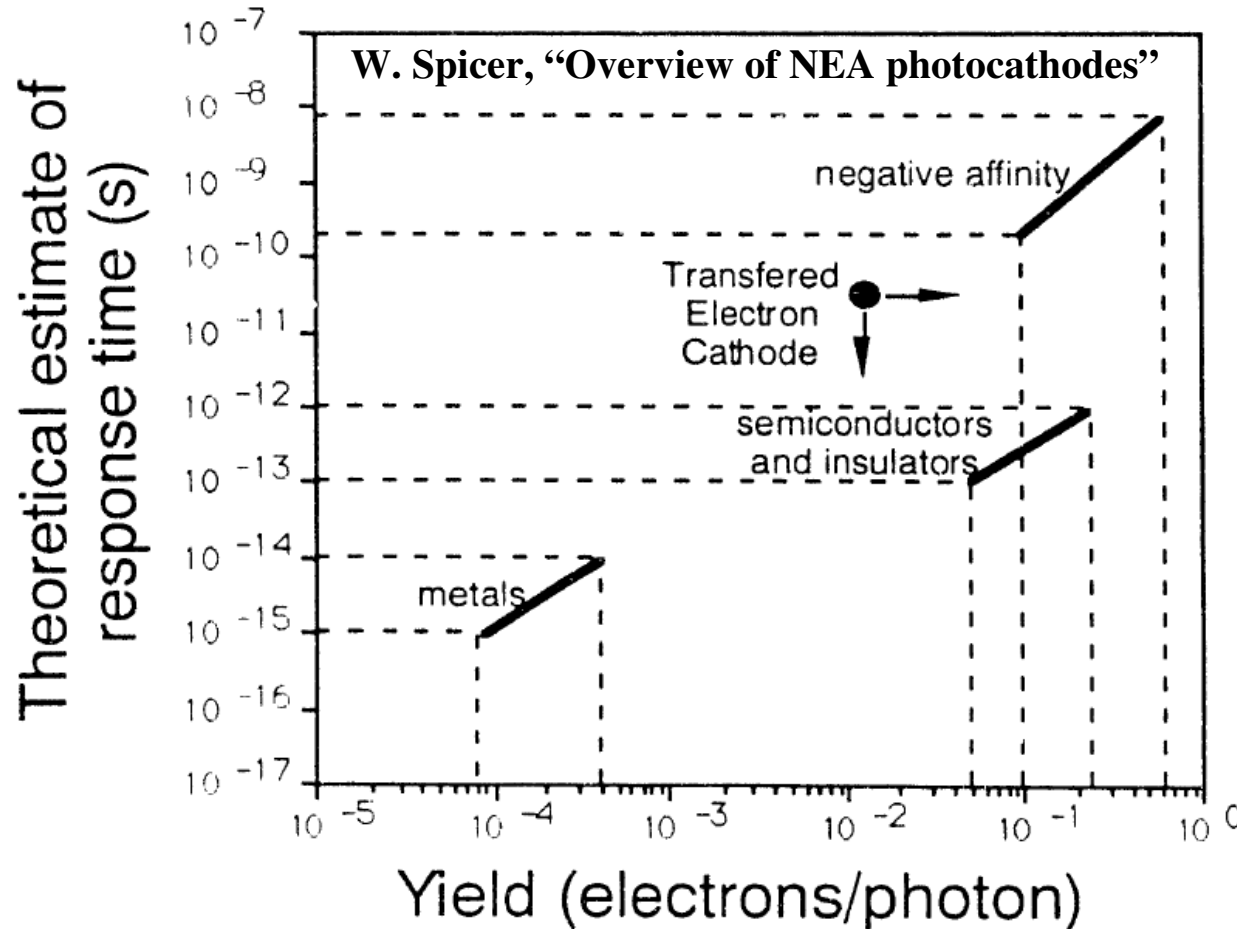




- When GaAs excited near the bandgap, electrons come out essentially thermalized ($kT \sim 30$ meV)
- Shorter wavelength \Rightarrow smaller thermalized fraction \Rightarrow larger kT
- GaAsP has larger kT than GaAs despite smaller $h\nu_{\text{ph}} - E_{\text{gap}}$
- GaAsP shows QE dependence for kT , GaAs does not show such dependence within the uncertainty of the measurement



- Traditionally, it was believed that NEA cathodes are slow (~ 10 s of ps); indeed, long emission tails were measured from GaAs for $\lambda \sim 850$ nm





$$\frac{\partial c(h, t)}{\partial t} = D \frac{\partial^2 c(h, t)}{\partial h^2}$$

subject to:

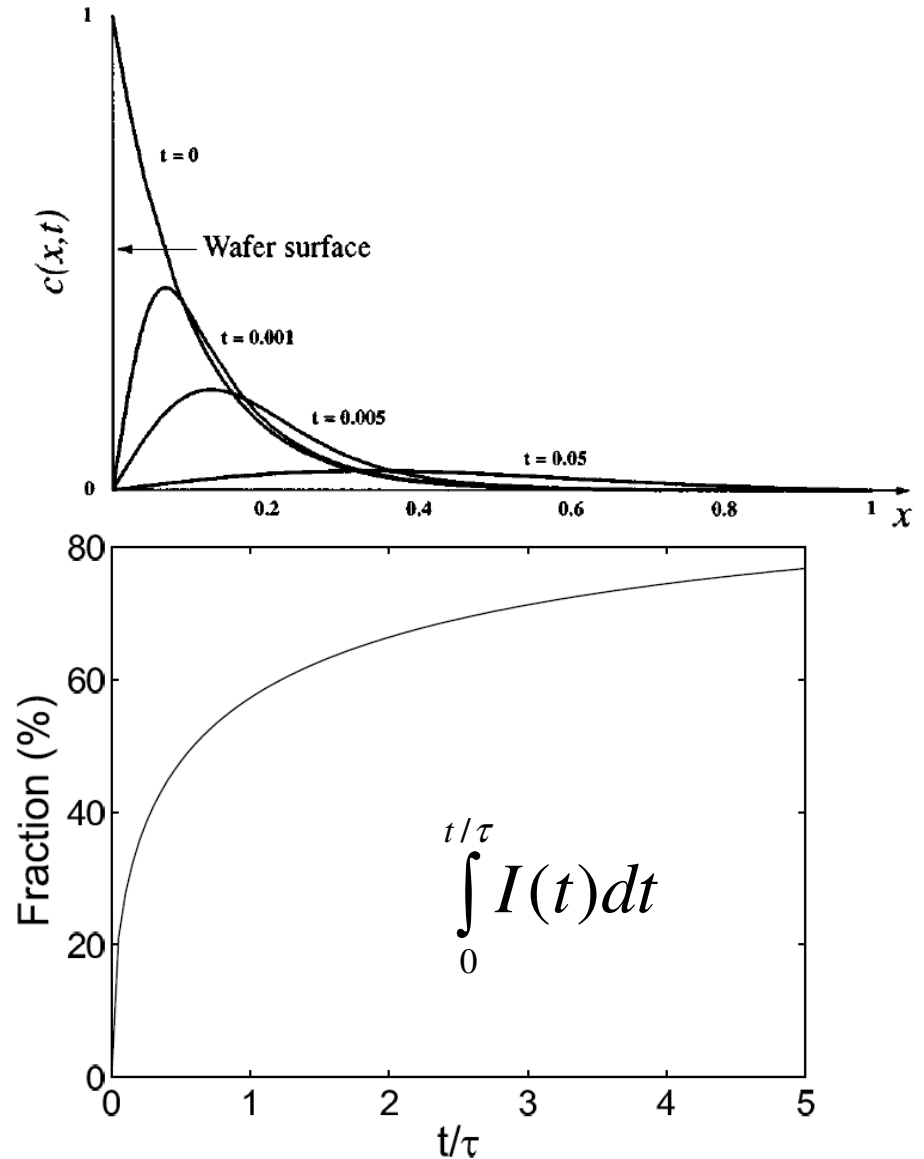
$$c(h, t = 0) = c_0 e^{-\alpha h}$$

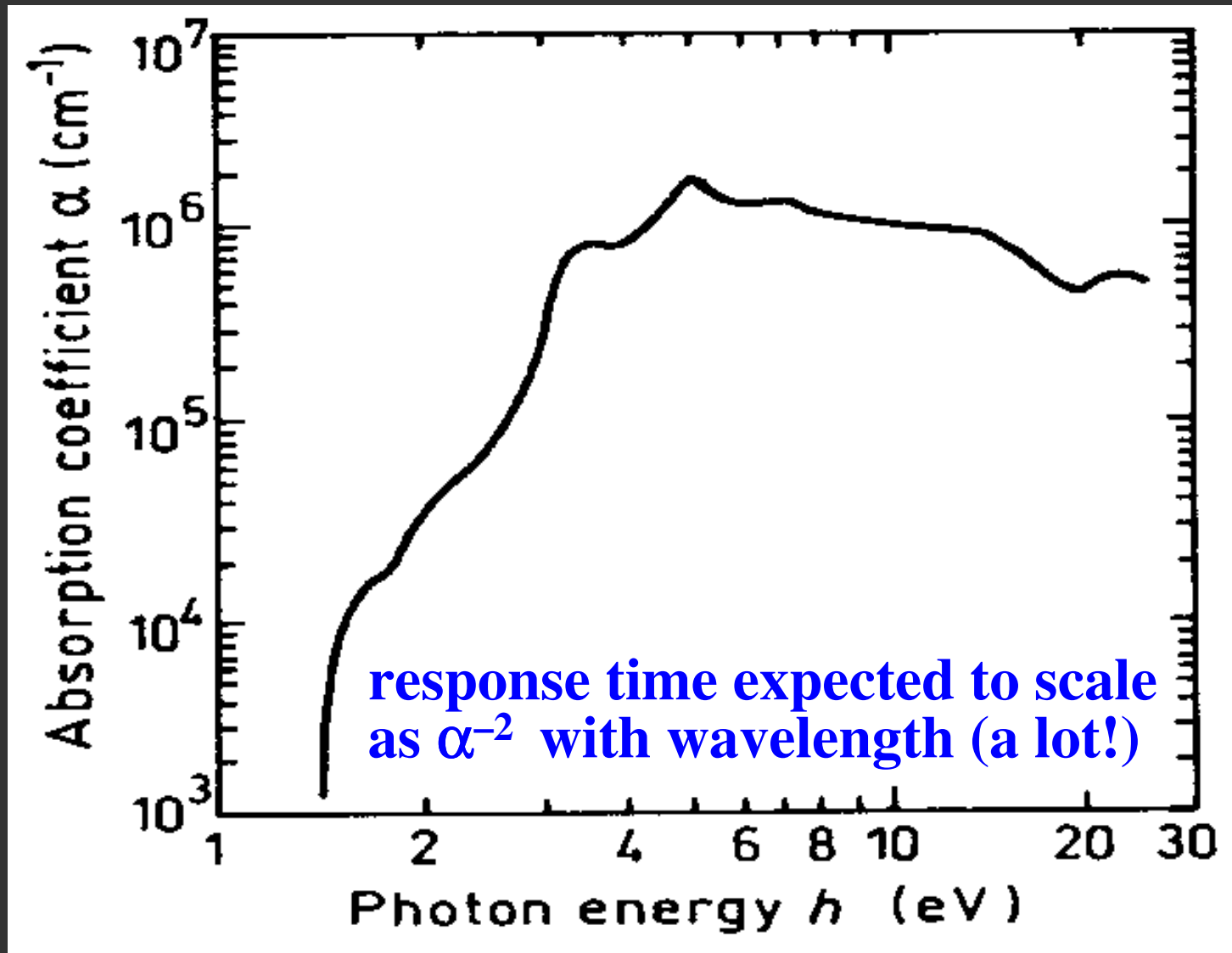
$$c(h = 0, t) = 0$$

$$I(t) \propto \frac{\partial}{\partial t} \int_0^{\infty} c(h, t) dh.$$

$$I(\kappa) \propto \frac{1}{\sqrt{\pi \kappa}} - \exp(\kappa) \operatorname{erfc}(\sqrt{\kappa})$$

$$\kappa \equiv t/\tau, \text{ where } \tau \equiv \alpha^{-2} D^{-1}$$





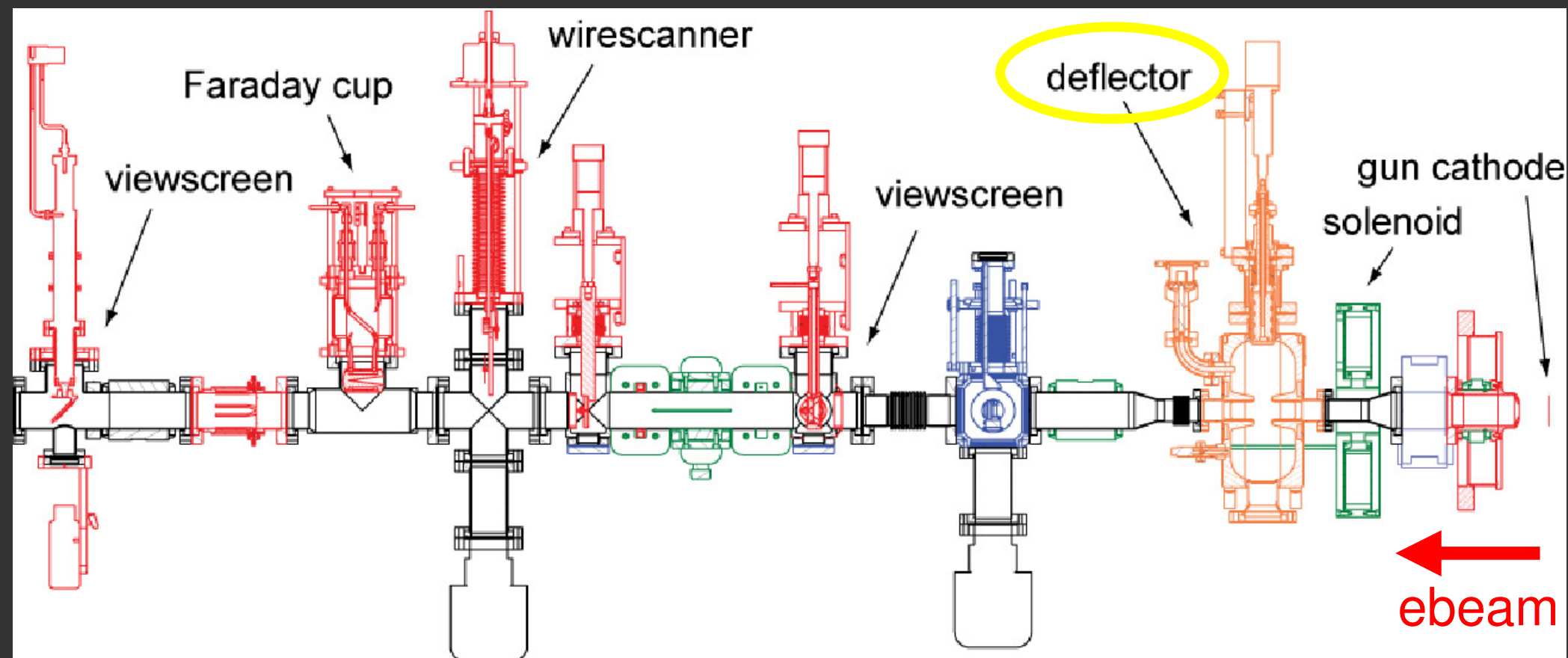


- Temporal response **directly measured** for **GaAs** and **GaAsP** for 520 nm (**1 ps rms laser pulse**)
- **Measured indirectly using space charge effect** for both photocathodes at 860, 785, 710, and 460 nm (**~100 fs laser pulse**)
- See Phys. Rev. ST-AB **11** (2008) 040702 for details



Setup (temp. response)

- RF synchronized to laser (1.2 ps rms jitter measured)
- Overall time resolution: 1.5 ps rms





- If solenoid is turned off, **shorter response time** \Rightarrow more space charge \Rightarrow **larger spot size**

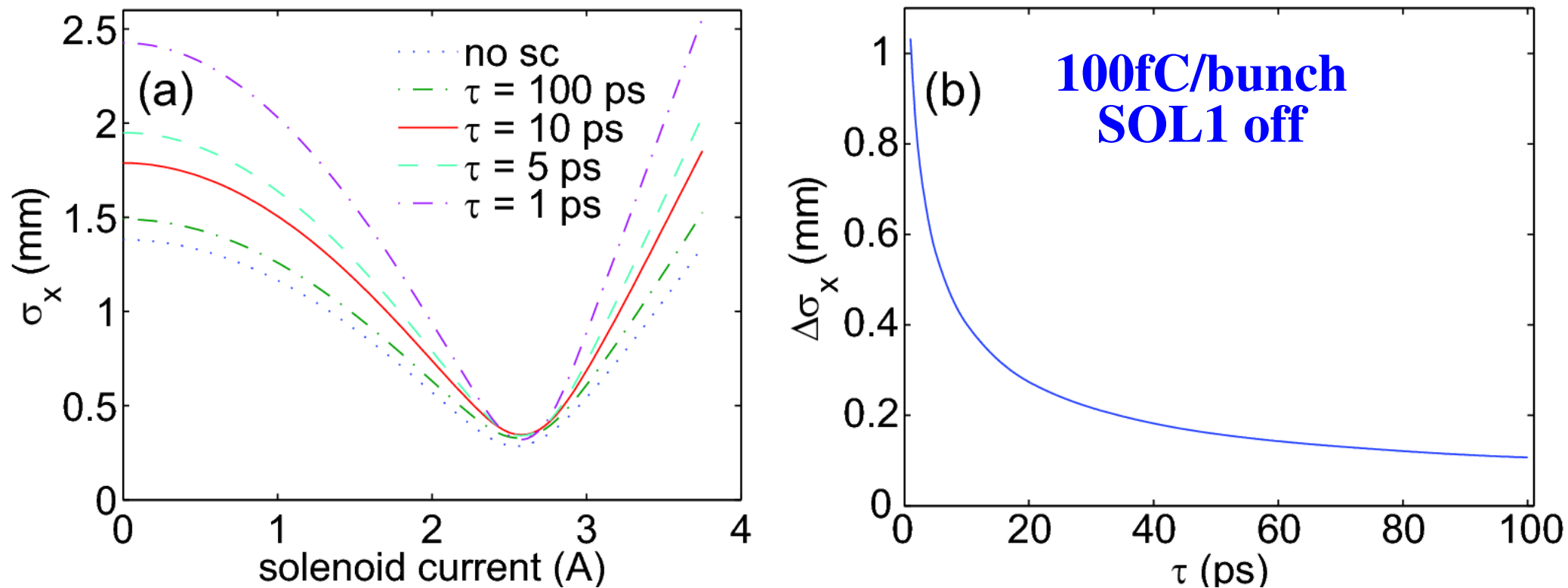
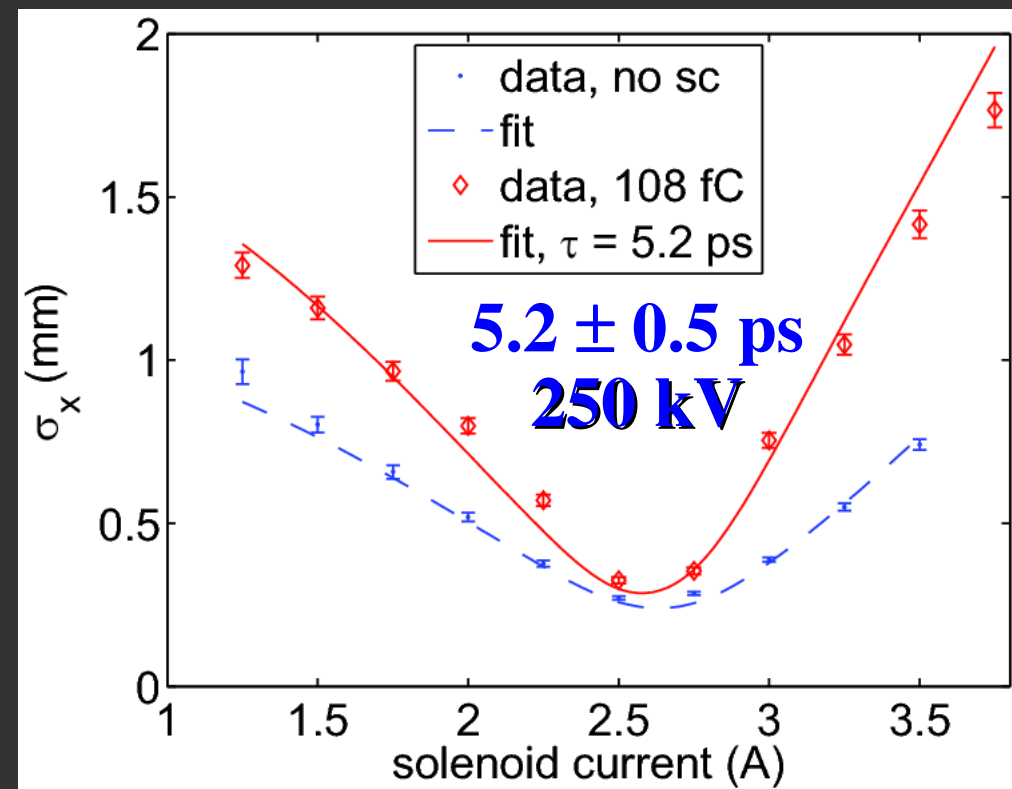
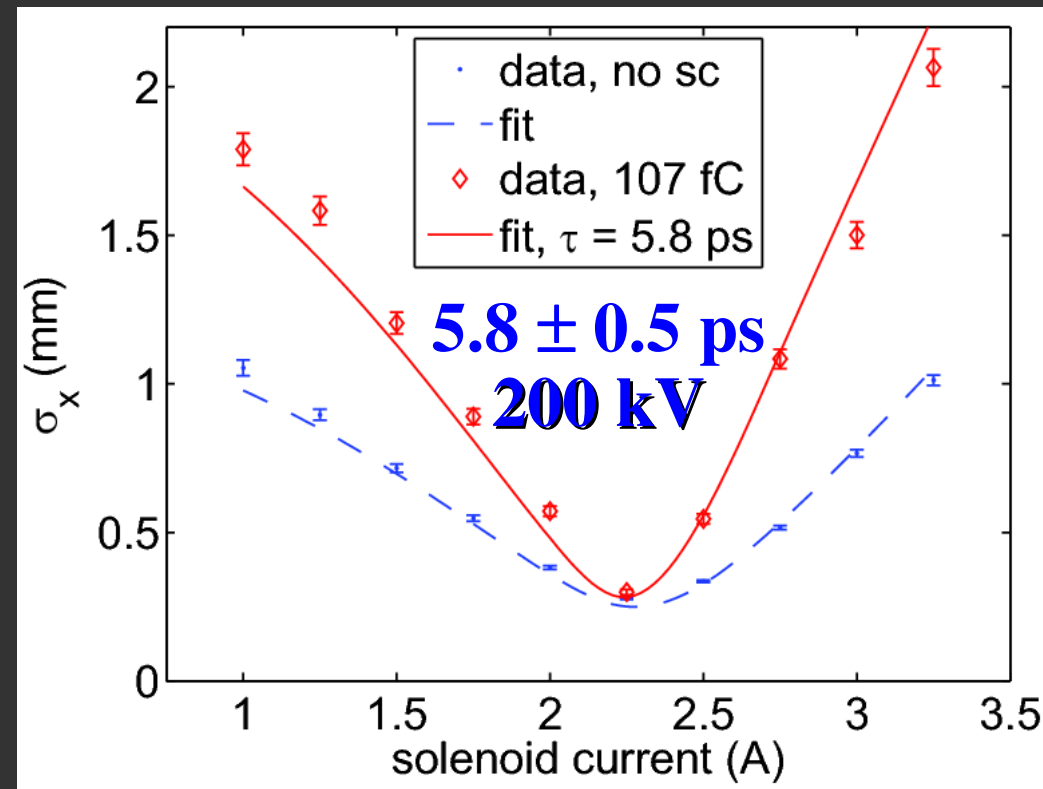


FIG. 11: Calculated dependence of the transverse beam size of the beam at the location of the wire scanner for different values of parameter τ . Charge per bunch 100 fC, gun voltage 250 kV, $k_B T_\perp$ 150 meV, initial rms laser spot size 120 μm . (a) Solenoid scan. (b) Change of the spot size relative to the case of negligible space charge for unpowered solenoid as a function of parameter τ .



- Used Astra with preprogrammed temporal profile (diffusion model + convolution with laser profile) to fit observed data (only one variable parameter)



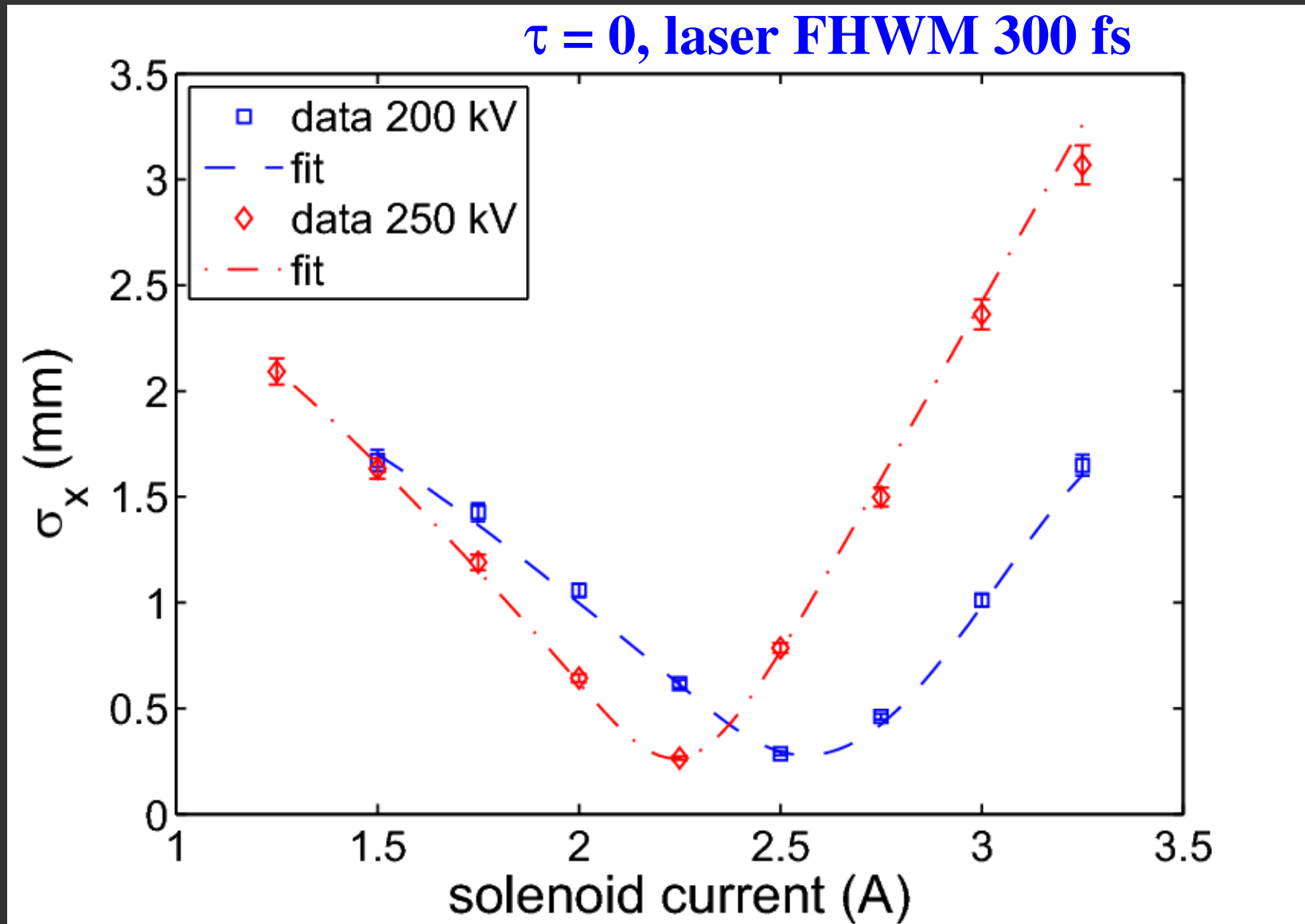


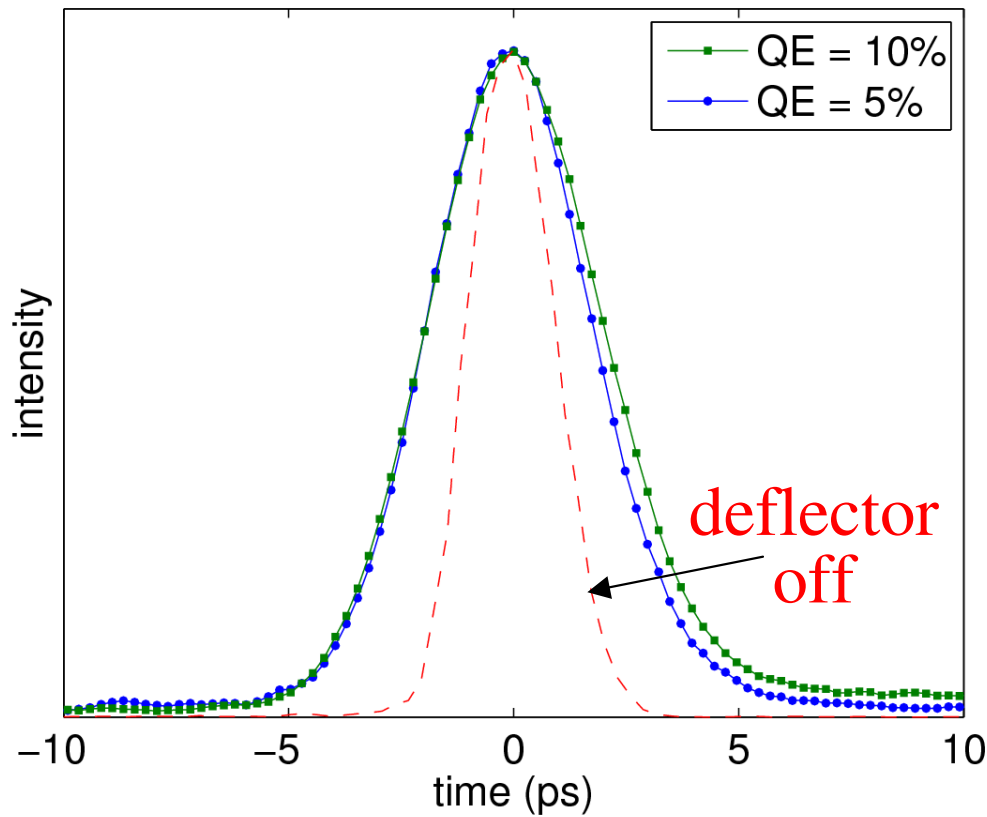


TABLE I: Results of data fitting for GaAs response time.

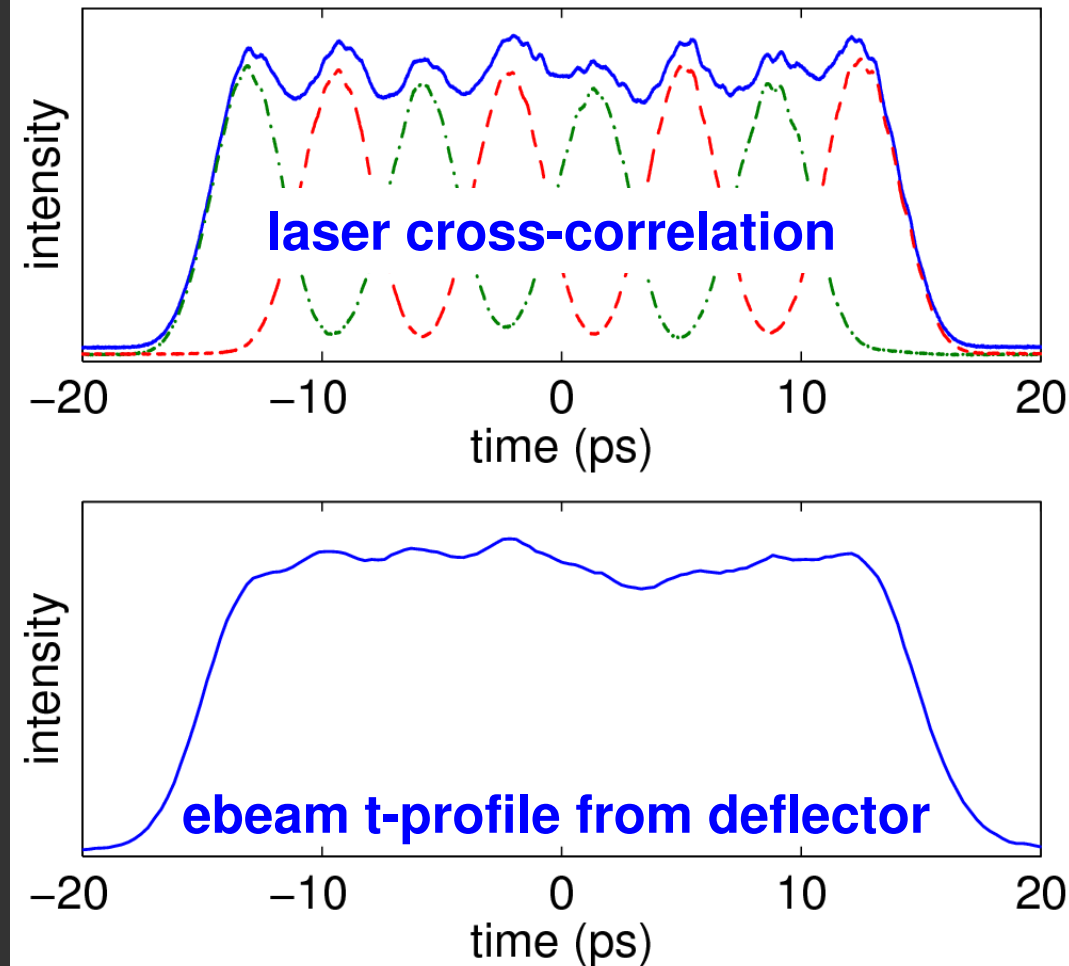
Wavelength (nm)	τ (ps)	Comment
860	76 ± 26	$V_{gun} = 200$ kV
860	69 ± 22	$V_{gun} = 250$ kV
785	11.5 ± 1.2	$V_{gun} = 200$ kV
785	9.3 ± 1.1	$V_{gun} = 250$ kV
710	5.8 ± 0.5	$V_{gun} = 200$ kV
710	5.2 ± 0.5	$V_{gun} = 250$ kV
520	≤ 1	upper estimate placed
460	≤ 0.14	upper estimate placed



response: 1ps rms laser

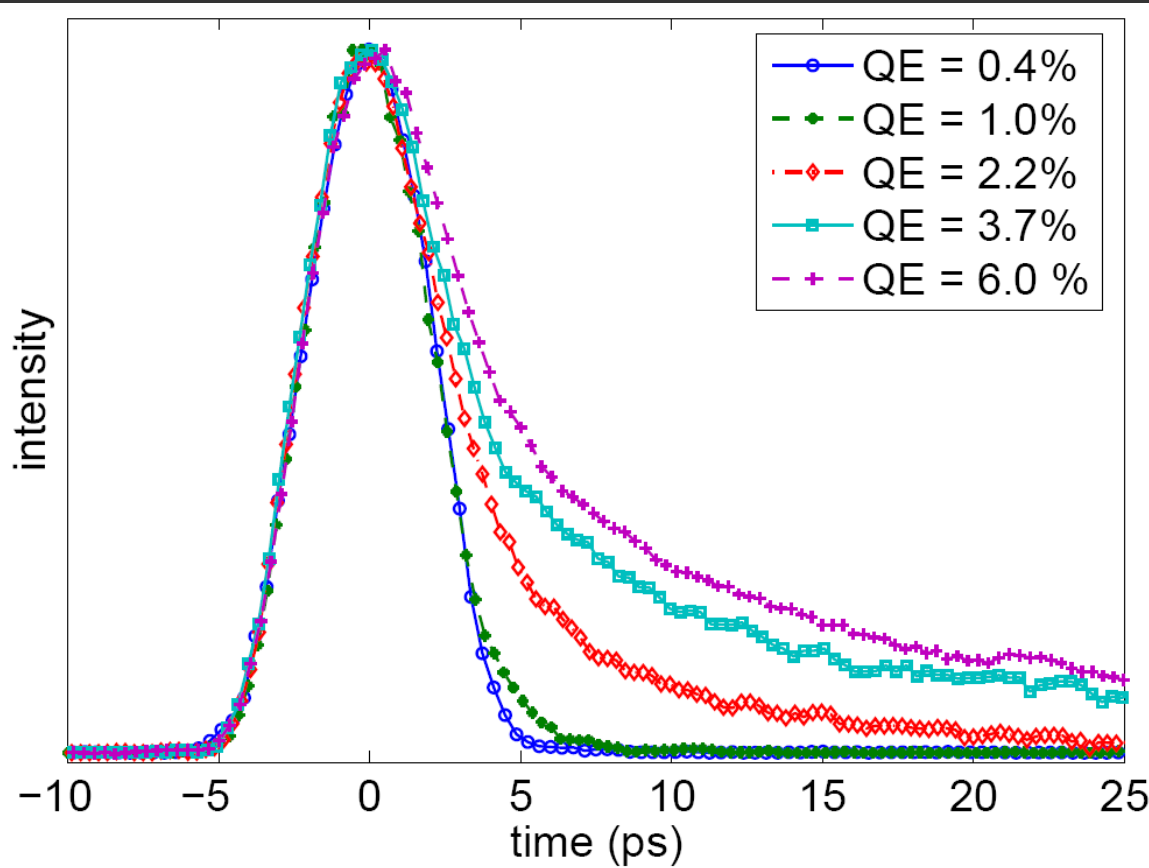


laser shaping

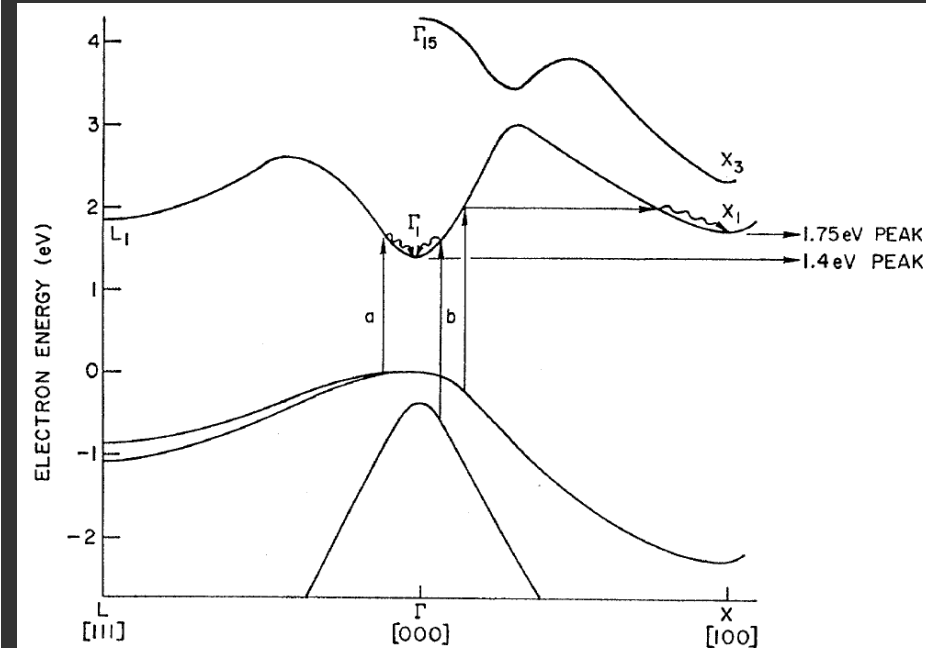




Strong QE dependency



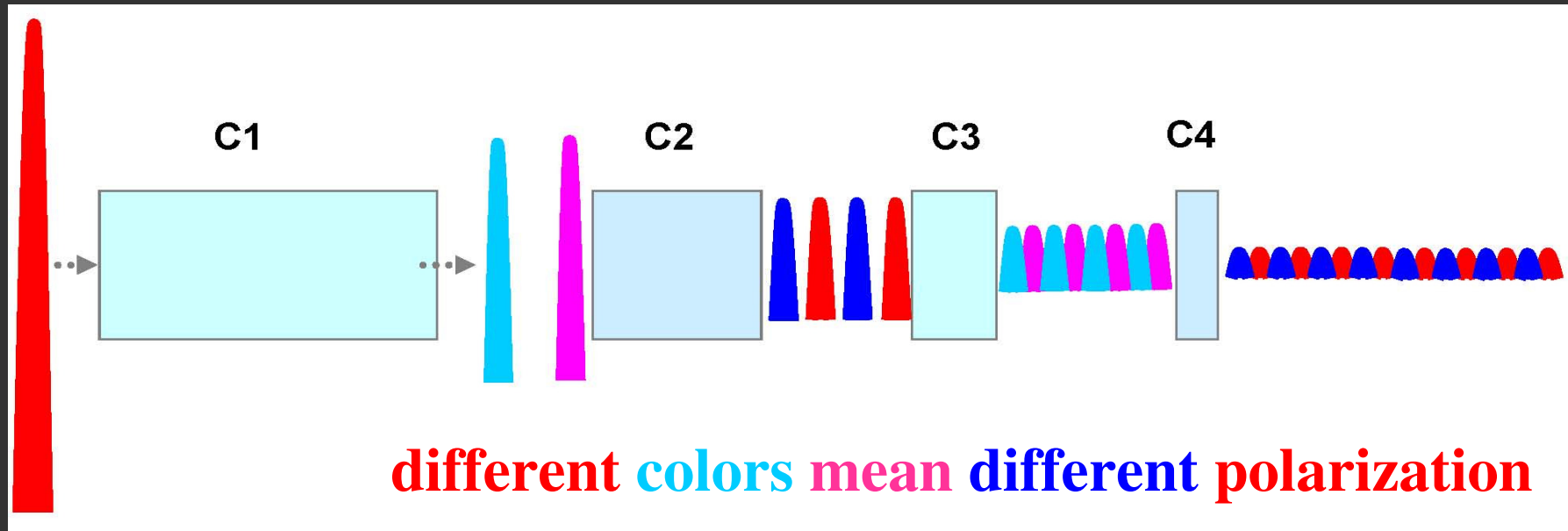
P concentration 45%



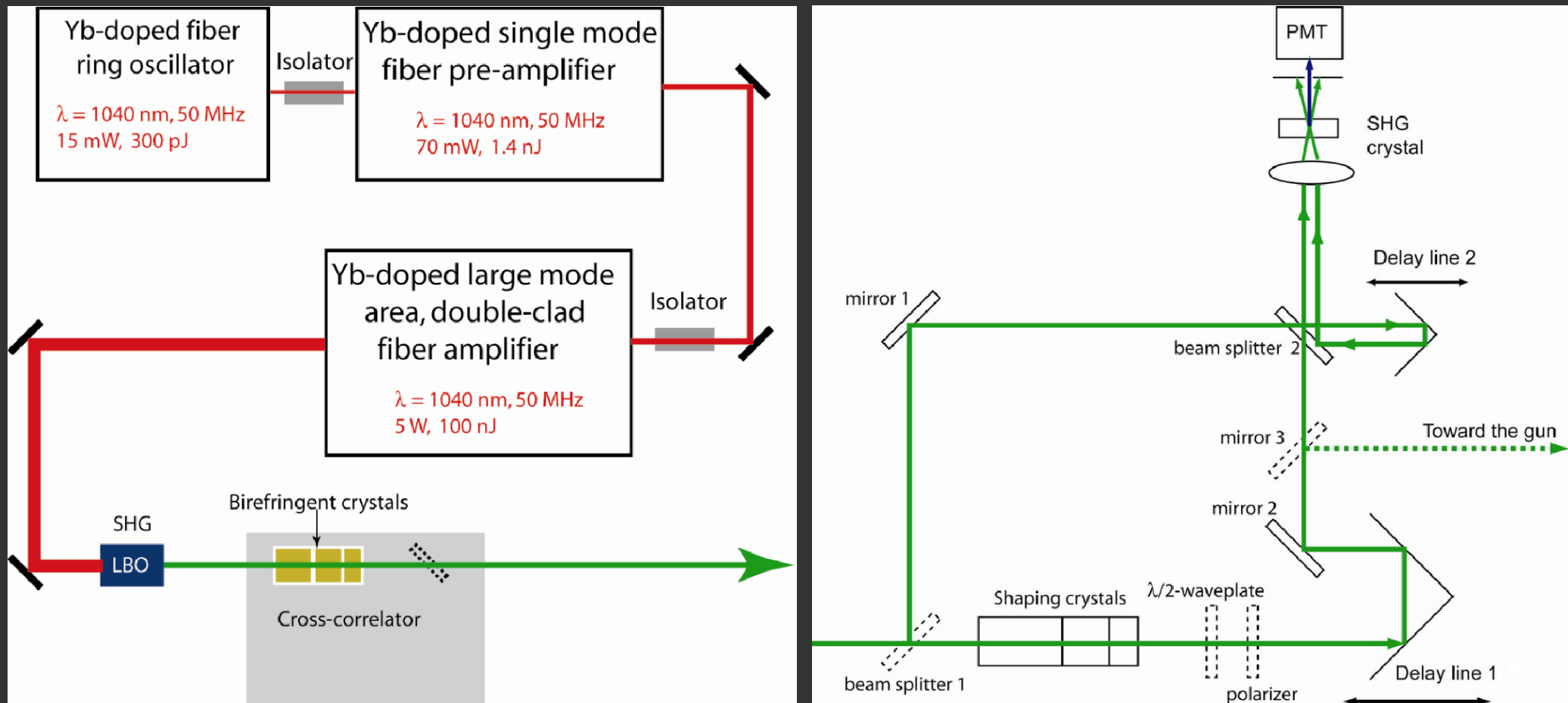
Two valleys: Γ (direct) and X (indirect) involved in the process

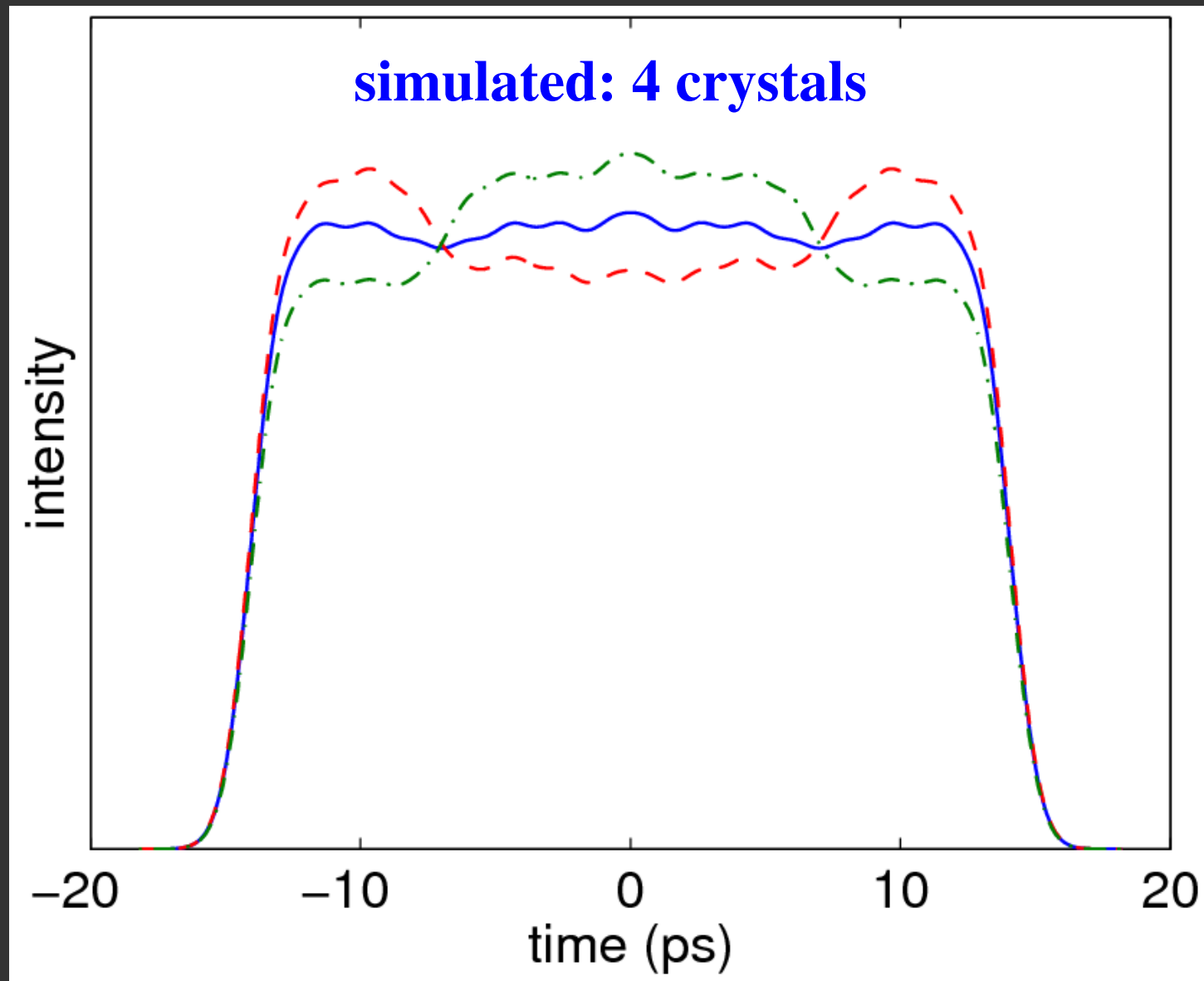


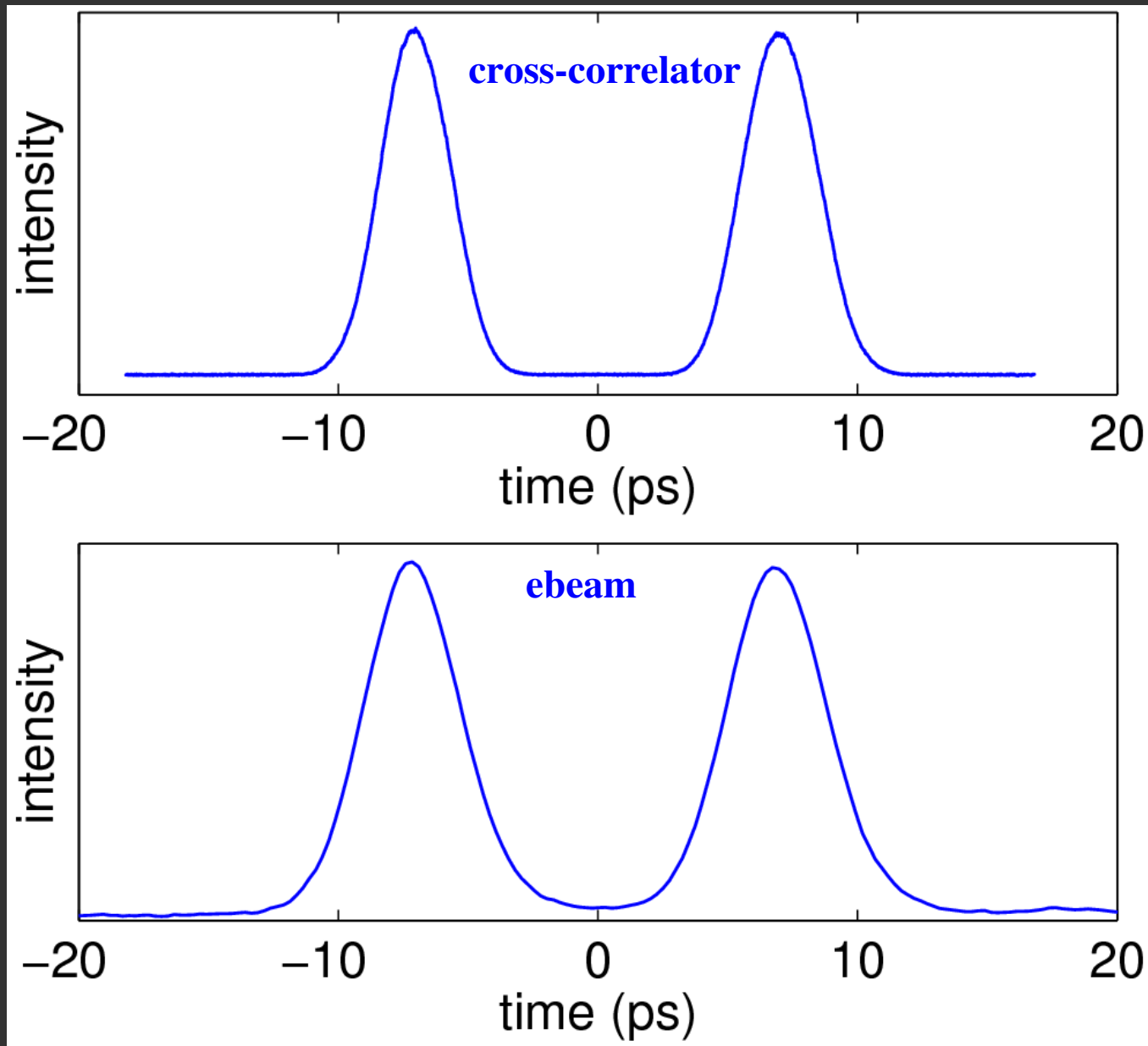
- **GaAs** is a **prompt emitter** (on ~ 1 ps scale) at **520 nm**
- GaAsP has longer tail (strong QE dependency) in addition to its larger thermal emittance
- This is thought to be due to emission from X CBM
- Also, have performed measurements on Cs:GaN photocathode at 260nm. Prompt emitter (on ~ 1 ps scale). Thermal emittance data is work in process.

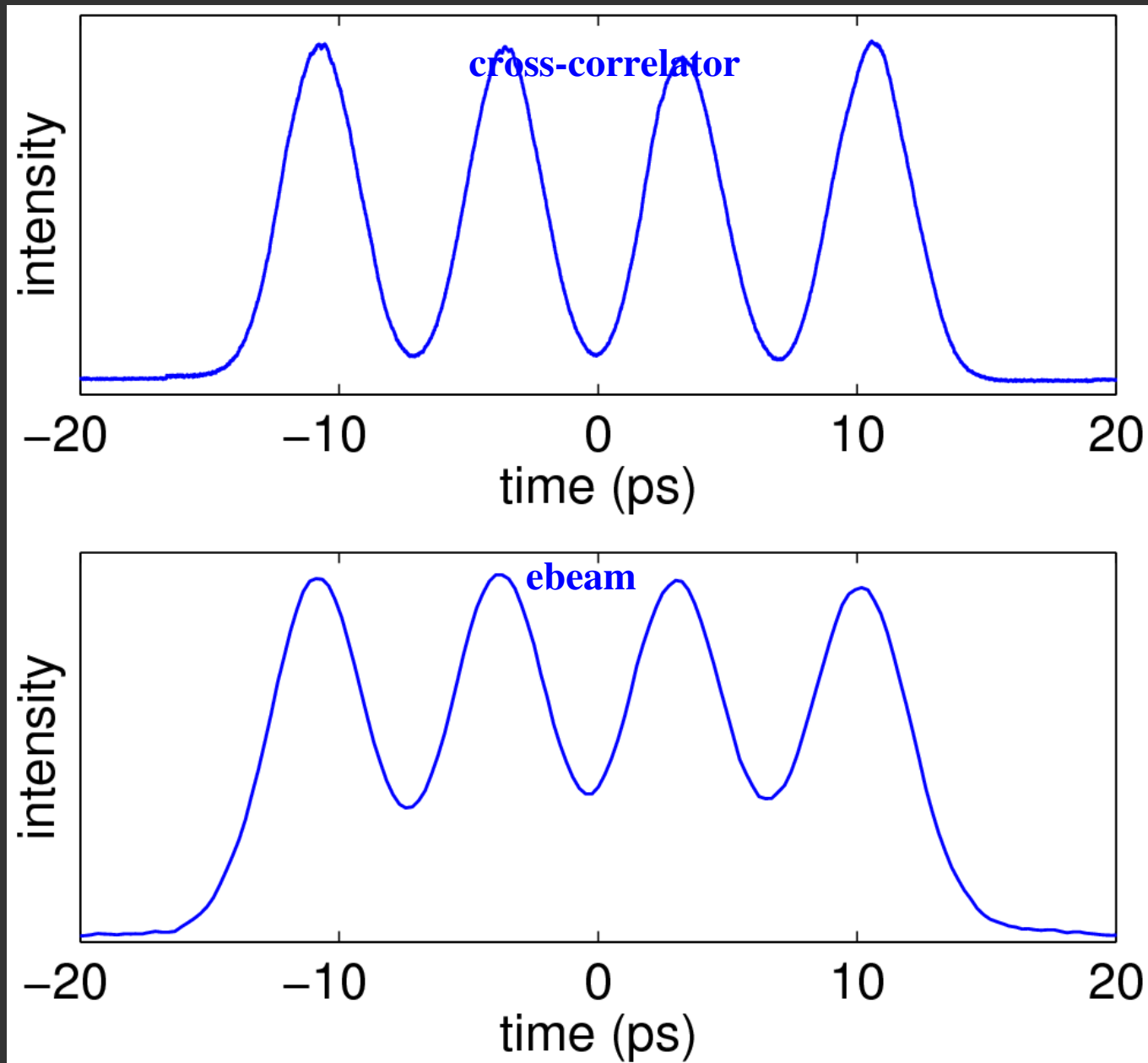


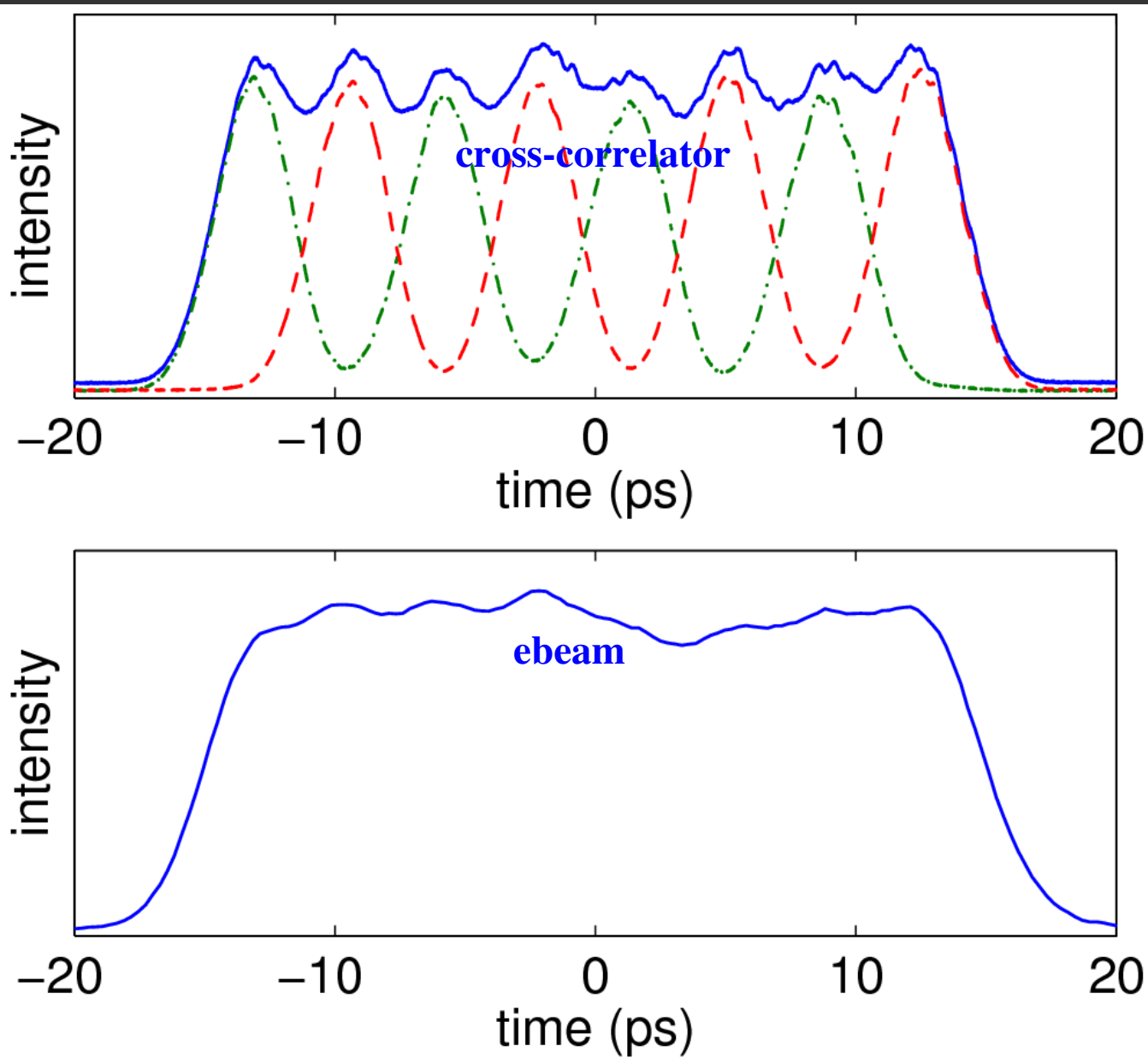
- Use birefringent crystals to shape short laser pulse (very efficient)













- Essential properties of NEA photocathodes have been measured in wide range of laser wavelengths
- GaAs is the superior choice of what we have tried so far; at **520 nm** the temporal response is **~ps** or shorter; thermal emittance is **0.48 mm-mrad per 1mm rms laser spot (4mm diameter spot)**



ERL team: John Barley, Sergey Belomestnykh, John Dobbins, Bruce Dunham, Fay Hannon, Yulin Li, Xianghong Liu, Bob Meller, Tsukasa Miyajima, Dimitre Ouzounov, Dave Rice, John Sikora, Charlie Sinclair, Karl Smolensky and more...

NSF for \$\$\$